

In the United States Patent and Trademark Office

Appn. Number: _____

Appn. Filed: _____

Applicant(s): Liphardt et al.

Appn. Title: Alignment of Ellipsometer Beam To Sample Surface

Examiner/GAU: _____ 1324

Mailed: With Application

At: _____

Information Disclosure Statement

Commissioner of Patents and Trademarks
Washington, District of Columbia 20231

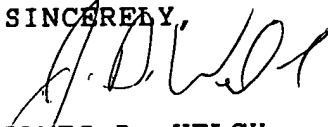
Sir:

Attached is a completed Form PTO-1449 and copies of the pertinent parts of the references cited thereon.
Following are comments on these references pursuant to Rule 98:

While a specific Search was not conducted, known Patents are disclosed to aid the Examination:

Patent to Coates No. 4,373,817;
Patent to Coates No. 5,045,704;
RE. 34,783 to Coates;
Patent to Mikkelsen et al., No. 6,600,560;
Patent to Fanton et al., No. 5,596,411;
Patent to Piwonka-Corle et al., No. 5,910,842;
Patent to Piwonka-Corle et al., No. 5,608,526;
Patent to Bareket, No. 5,889,593;
Patent to Norton et al., No. 5,486,701;
Patent to Aspnes et al., No. 5,900,939;
PCT Application Publication WO 99/45340;
Published Application of Stehle et al., No.
US2002/0024668 A1;

SINCERELY,


JAMES D. WELCH

REG. NO. 31,216

ATTY. DOCKET NO.

SERIAL NO.

LIST OF PRIOR ART CITED BY APPLICANT
(Use several sheets if necessary)

APPLICANT

Liphardt et al.

FILING DATE

GROUP

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
AA	4373817	2/1983	Coater	356	384	
AB	5045704	9/1991	Coater	250	372	
AC	RE34783	11/1994	Coater	250	372	
AD	6600560	7/2003	Mithelsen et al.	356	369	
AE	5596411	1/1997	Fanton et al.	356	369	
AF	5910842	6/1999	Piwonka-Corle et al.	356	369	
AG	5608526	3/1997	Piwonka-Corle et al.	356	364	
AH	5889593	3/1999	Bareh	356	445	
AI	5486701	1/1996	Norton et al.	250	372	
AJ	5900939	5/1999	Aspnes et al.	356	369	
AK						

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
AL							
AM							

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

AR	FLA-Tencer WO 99/45340
AS	Stehle et al. US Published App. US 2002/0024668 A1

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 607; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.